



Gallium Nitride 50V, 650W, 3.4-3.8GHz RF Power Transistor

Description

The STCV38650CY4V is a 650-watt, internally matched GaN HEMT, designed for 5G cellular applications with frequencies from 3.4-3.8GHz, **enabled by wide band VBW capability to support IBW up to 200MHz.**

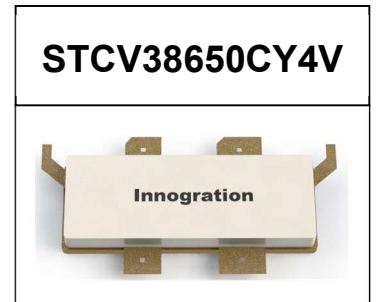
It can be configured as asymmetrical Doherty for 4G or 5G application, delivering 80-100W average power, according to normal 8 to 9dB back off.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical Doherty Pulsed CW and 1C W--CDMA Characterization Performance:

$V_{DD} = 50 \text{ Vdc}$, $I_{DQA} = 280 \text{ mA}$, $V_{GSB} = -6.4 \text{ Vdc}$,

1C WCDMA; Signal PAR = 10 dB @ 0.01% Probability on CCDF.



| Freq (GHz) | Pulse CW Signal ⁽¹⁾ | | | | $P_{avg} = 48.5 \text{ dBm}$ WCDMA Signal ⁽²⁾ | | |
|------------|--------------------------------|--------|----------|--------|--|--------------|--------------------------|
| | P1 (dBm) | P1 (W) | P3 (dBm) | P3 (W) | Gp (dB) | η_D (%) | ACPR _{5M} (dBc) |
| 3.40 | 56.92 | 492 | 58.22 | 663 | 10.58 | 41.42 | -33.51 |
| 3.50 | 58.31 | 678 | 58.57 | 711 | 11.11 | 41.02 | -34.56 |
| 3.60 | 57.73 | 593 | 58.52 | 711 | 11.46 | 43.32 | -34.88 |
| 3.70 | 56.31 | 428 | 58.35 | 683 | 11.31 | 42.43 | -37.75 |
| 3.80 | 58.04 | 636 | 58.16 | 655 | 11.16 | 41.49 | -31.20 |

Applications

- Asymmetrical Doherty amplifier within N77/78 5G band
- S band power amplifier

Important Note: Proper Biasing Sequence for GaN HEMT Transistors

Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Figure 1: Pin Connection definition

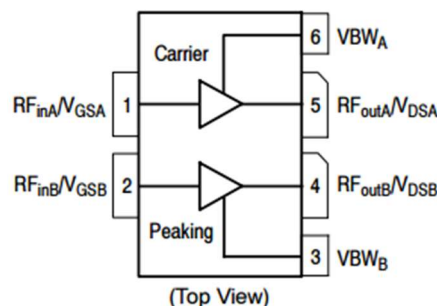




Table 1. Maximum Ratings

| Rating | Symbol | Value | Unit |
|--------------------------------|-----------|-------------|------|
| Drain—Source Voltage | V_{DSS} | +200 | Vdc |
| Gate—Source Voltage | V_{GS} | -8 to +0.5 | Vdc |
| Operating Voltage | V_{DD} | 55 | Vdc |
| Maximum gate current | I_{gs} | 85 | mA |
| Storage Temperature Range | T_{stg} | -65 to +150 | °C |
| Case Operating Temperature | T_c | +150 | °C |
| Operating Junction Temperature | T_J | +225 | °C |

Table 2. Thermal Characteristics

| Characteristic | Symbol | Value | Unit |
|---|-----------------|-------|-------|
| Thermal Resistance, Junction to Case by FEA $T_c=85^\circ\text{C}$, $P_{out}=80\text{W}$, 3.8GHz Doherty application board | $R_{\theta JC}$ | 0.8 | °C /W |

Table 3. Electrical Characteristics (TA = 25°C unless otherwise noted)

DC Characteristics (main path, measured on wafer prior to packaging)

| Characteristic | Conditions | Symbol | Min | Typ | Max | Unit |
|--------------------------------|--|--------------|-----|------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS}=-8\text{V}$; $I_{DS}=34\text{mA}$ | V_{DSS} | | 200 | | V |
| Gate Threshold Voltage | $V_{DS}=10\text{V}$, $I_D=34\text{mA}$ | $V_{GS(th)}$ | -4 | | -2 | V |
| Gate Quiescent Voltage | $V_{DS}=50\text{V}$, $I_{DS}=280\text{mA}$, Measured in Functional Test | $V_{GS(Q)}$ | | -3.2 | | V |

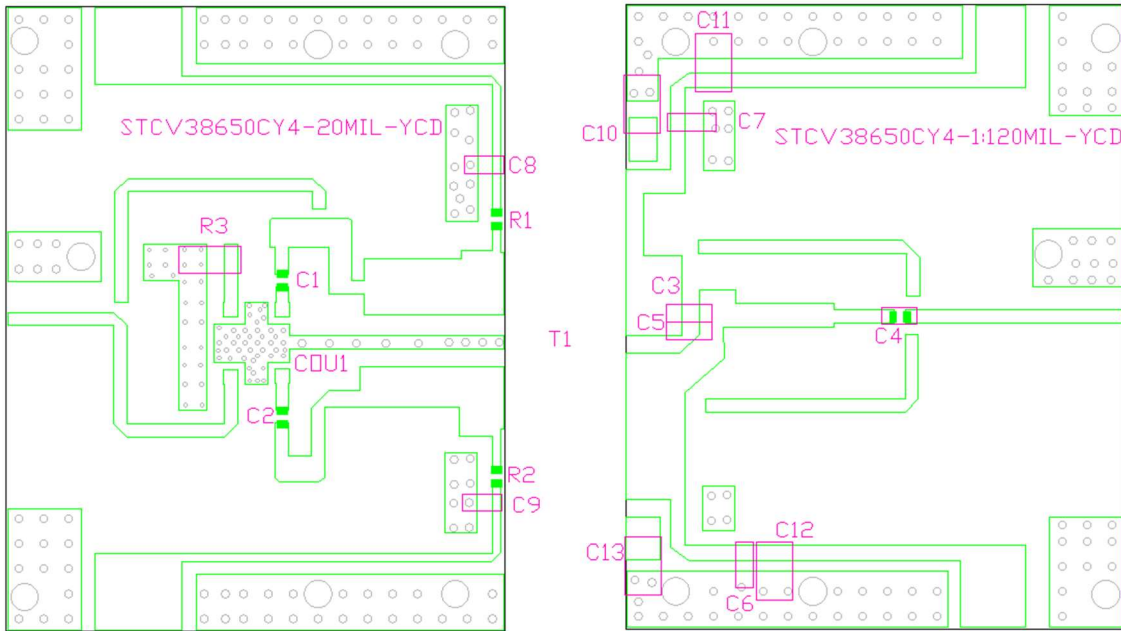
DC Characteristics (peak path, measured on wafer prior to packaging)

| Characteristic | Conditions | Symbol | Min | Typ | Max | Unit |
|--------------------------------|--|--------------|-----|------|-----|------|
| Drain-Source Breakdown Voltage | $V_{GS}=-8\text{V}$; $I_{DS}=51\text{mA}$ | V_{DSS} | | 200 | | V |
| Gate Threshold Voltage | $V_{DS}=10\text{V}$, $I_D=51\text{mA}$ | $V_{GS(th)}$ | -4 | | -2 | V |
| Gate Quiescent Voltage | $V_{DS}=50\text{V}$, $I_{DS}=420\text{mA}$, Measured in Functional Test | $V_{GS(Q)}$ | | -3.2 | | V |

Ruggedness Characteristics

| Characteristic | Conditions | Symbol | Min | Typ | Max | Unit |
|--------------------------|---|--------|-----|------|-----|------|
| Load mismatch capability | 3.8GHz, $P_{out}=80\text{W}$ WCDMA 1 Carrier in Doherty circuit All phase, No device damages | VSWR | | 10:1 | | |

Figure 3: Picture of application board Doherty circuit for 3.8-4.2GHz



| Part | Quantity | Description | Part Number | Manufacture |
|--------------------------|----------|---------------------------|-----------------|--------------|
| C1,C2,C4,C6, C7,C8,C9 | 7 | 8.2pF High Q Capacitor | 251SHS8R2BSE | TEMEX |
| C3,C5 | 2 | 1.1pF High Q Capacitor | ATC600S1R1 | ATC |
| C10,C11,C12,C13 | 4 | 10uF MLCC | RS80R2A106M | MARUWA |
| R1,R2 | 2 | 10 Ω Power Resistor | ESR03EZPF100 | ROHM |
| R3 | 1 | 51 Ω Power Resistor | RFR50-20CT0421B | YT |
| COU1 | 1 | 3 dB Bridge | XC3500P-03S | ANAREN |
| T1 | 1 | 650W GaN | STCV38650CY4V | Innogrations |

Figure 4: Intermodulation Distortion Products versus Two-Tone Spacing

V_{dd}=50V, P_{out}=48.5dBm, Center Frequency=3.6GHz

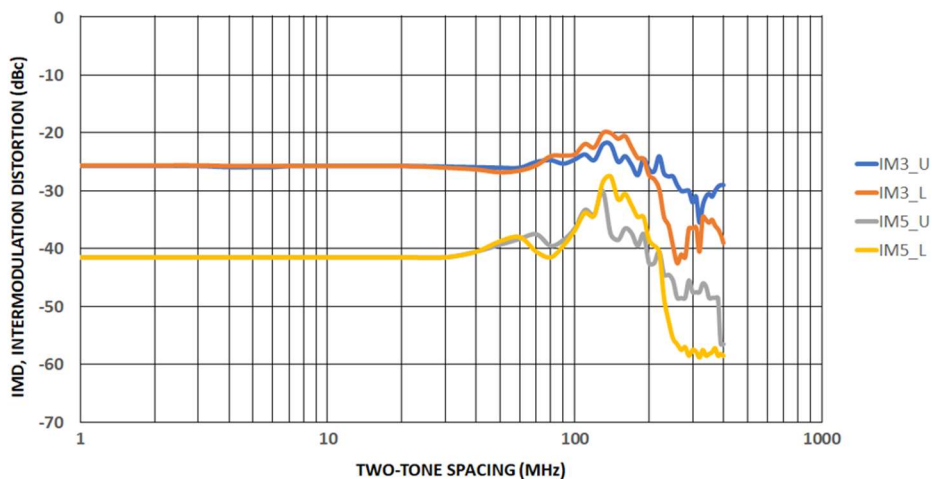




Figure 5: Efficiency and power gain as function of Pout

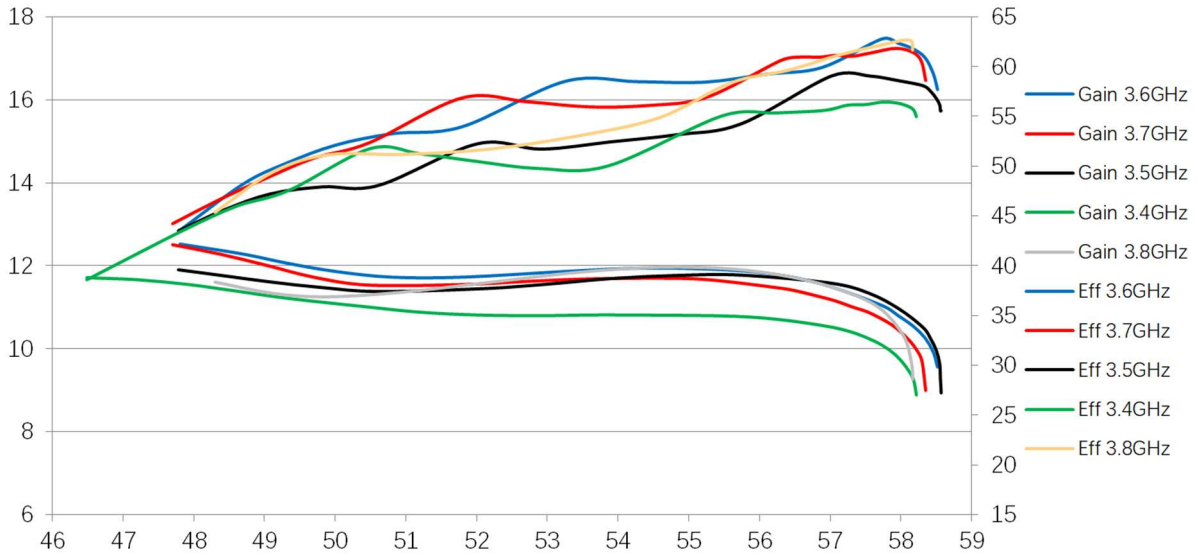
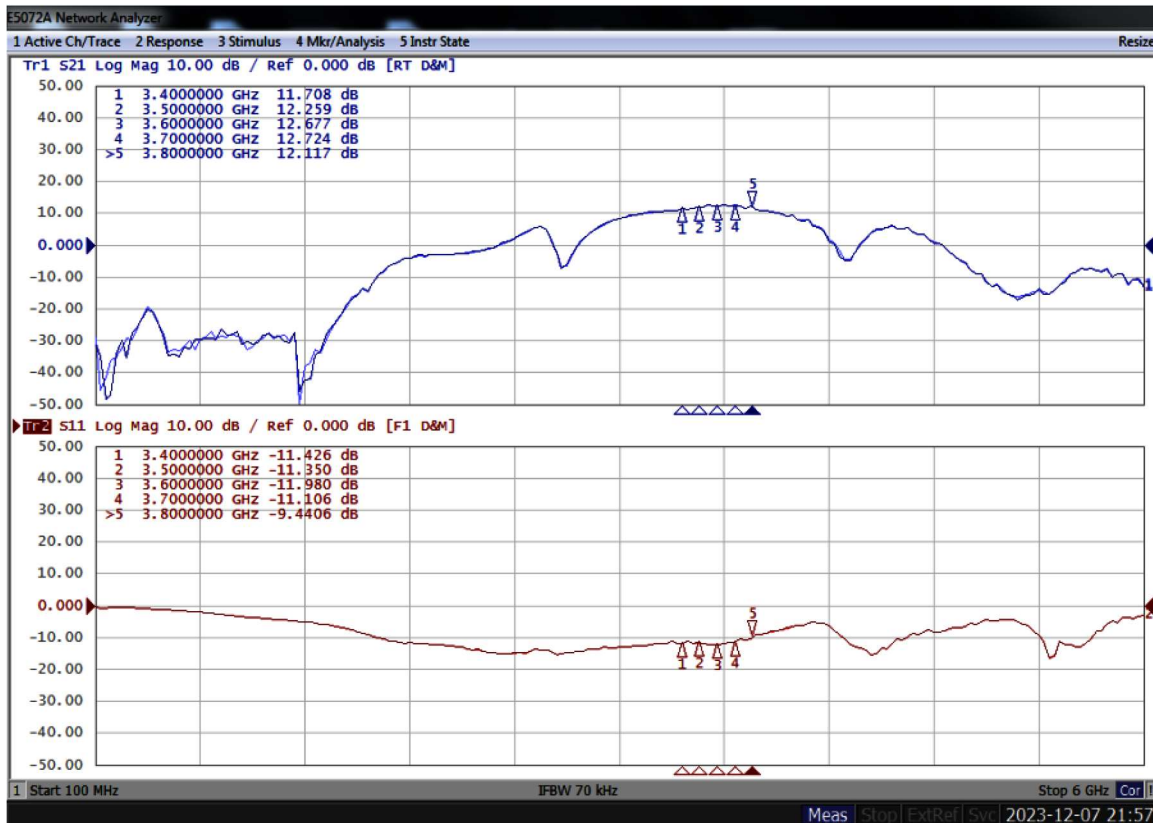
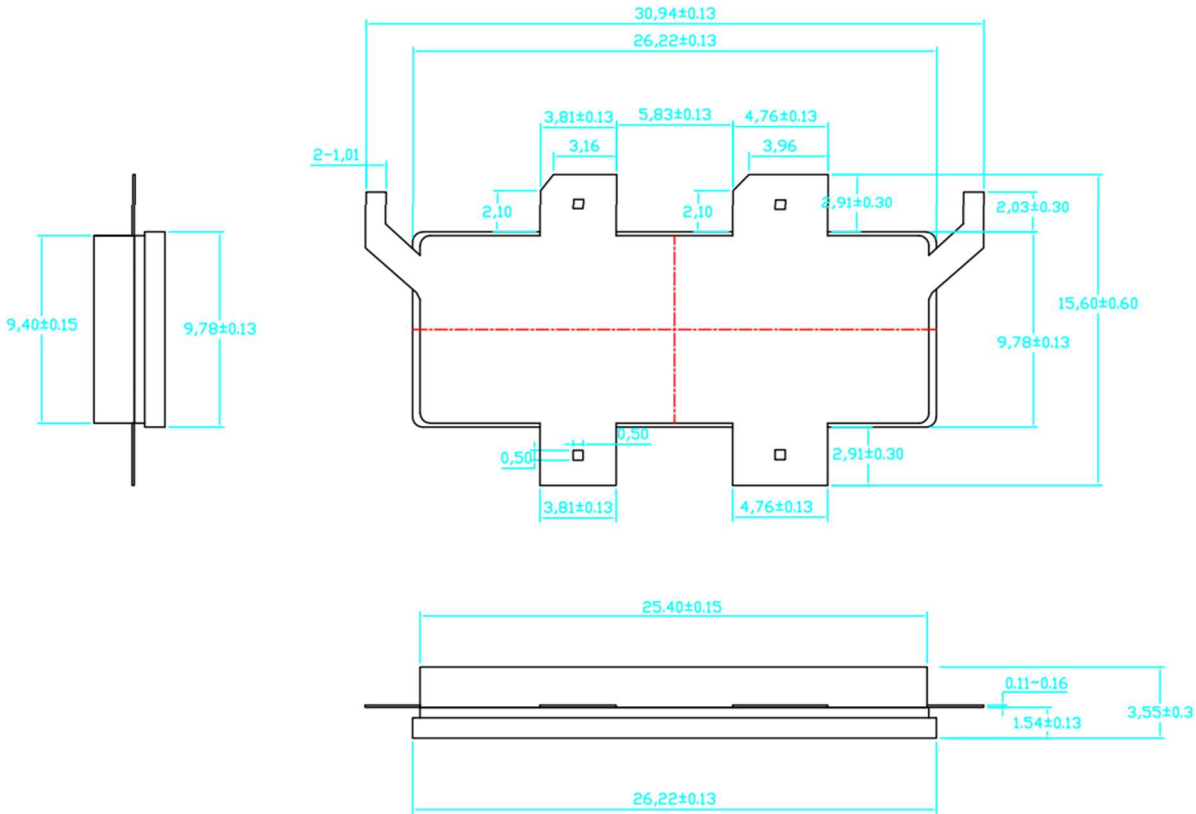


Figure 6: Network analyzer output, S11 and S21





Earless Flanged Ceramic Package; 6 leads- CY4V



Revision history

Table 4. Document revision history

| Date | Revision | Datasheet Status |
|-----------|----------|--------------------------------|
| 2023/12/9 | V1.0 | Preliminary Datasheet Creation |
| | | |
| | | |
| | | |

Application data based on LWH-23-25

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